

P-Channel Enhancement Mode Power MOSFET

Description

The HM25P15K uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

General Features

● V_{DS} =-150V,I_D =-25A

 $R_{DS(ON)}\,{<}135m\Omega\;\textcircled{0}\;V_{GS}\text{=-}10V\quad(\text{Typ.=}120mR)$

 $R_{DS(ON)}$ <160m Ω @ V_{GS} =-4.5V (Typ.=131mR)

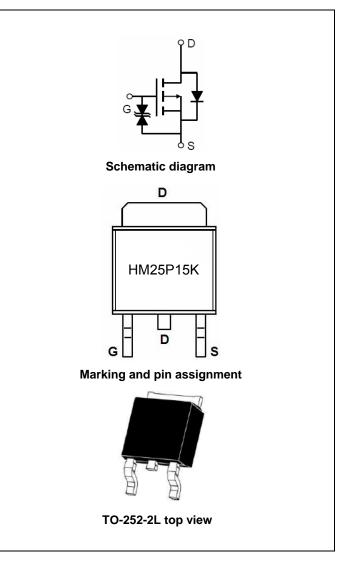
- Super high dense cell design
- Advanced trench process technology
- Reliable and rugged
- High density cell design for ultra low On-Resistance

Application

Portable equipment and battery powered systems

100% UIS TESTED!

100% ΔVds TESTED!



Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
HM25P15K	HM25P15K	TO-252-2L	Ø330mm	12mm	2500 units

Absolute Maximum Ratings (T_C=25 ℃unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	-150	V
Gate-Source Voltage	V _G S	±20	V
Drain Current-Continuous	I _D	-25	Α
Drain Current-Continuous(T _C =100℃)	I _D (100℃)	-17	Α
Pulsed Drain Current	I _{DM}	-140	Α
Maximum Power Dissipation	P _D	160	W
Derating factor		1.3	W/°C
Operating Junction and Storage Temperature Range	T_{J}, T_{STG}	-55 To 150	$^{\circ}$

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Thermal Characteristic

Electrical Characteristics (T_C=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics	<u>.</u>		•			
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =-250μA	-145	-155	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =-145V,V _{GS} =0V	-	-	1	μΑ
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V	-	-	±10	μΑ
On Characteristics (Note 3)	cteristics (Note 3)					
Gate Threshold Voltage	V _{GS(th)}	$V_{DS}=V_{GS}$, $I_{D}=-250\mu A$	-1.5	-1.9	-3	V
Drain-Source On-State Resistance	Б	V _{GS} =-10V, I _D =-20A	OA - 120 135		135	mΩ
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =-4.5V, I _D =-20A		131	160	
Forward Transconductance	g FS	V _{DS} =-5V,I _D =-20A	5	-	-	S
Dynamic Characteristics (Note4)						
Input Capacitance	C _{lss}	\/ - 75\/\/ -0\/	-	7650	-	PF
Output Capacitance	C _{oss}	V_{DS} =-75V, V_{GS} =0V, F=1.0MHz	-	148	-	PF
Reverse Transfer Capacitance	C _{rss}	F-1.UIVITZ	-	131	-	PF
Switching Characteristics (Note 4)			•			
Turn-on Delay Time	t _{d(on)}		-	17	-	nS
Turn-on Rise Time	t _r	V_{DD} =-75 V , I_{D} =-20 A	-	80	-	nS
Turn-Off Delay Time	t _{d(off)}	V_{GS} =-10 V , R_{GEN} =9.1 Ω	-	45	-	nS
Turn-Off Fall Time	t _f		-	65	-	nS
Total Gate Charge	Qg	\/ - 75\/ - 204	-	137	-	nC
Gate-Source Charge	Q _{gs}	V_{DS} =-75V, I_{D} =-20A, V_{GS} =-10V	-	25	-	nC
Gate-Drain Charge	Q _{gd}	VGS=-10V	-	28	-	nC
Drain-Source Diode Characteristics			•			
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =-25A	-	-	-1.2	V
Diode Forward Current (Note 2)	Is	-	-	-	-25	Α
Reverse Recovery Time	t _{rr}	TJ = 25°C, IF =-25A	-	90	-	nS
Reverse Recovery Charge	Qrr	$di/dt = 100A/\mu s^{(Note3)}$	-	105	-	nC

Notes:

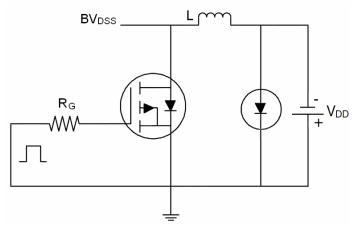
- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, t ≤ 10 sec.
- 3. Pulse Test: Pulse Width ≤ 300µs, Duty Cycle ≤ 2%.
- **4.** Guaranteed by design, not subject to production
- **5.** EAS condition: Tj=25 $^{\circ}$ C,V_{DD}=-75V,V_G=-10V,L=0.5mH,Rg=25 Ω

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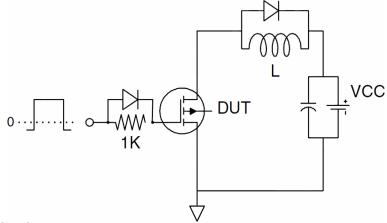


Test Circuit

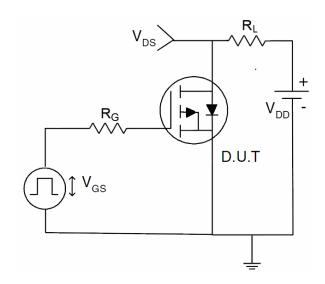
1) E_{AS} Test Circuit



2) Gate Charge Test Circuit



3) Switch Time Test Circuit



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Typical Electrical and Thermal Characteristics (Curves)

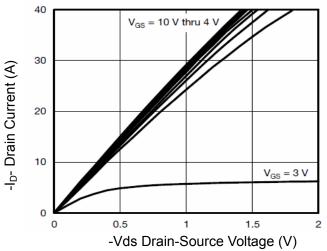


Figure 1 Output Characteristics

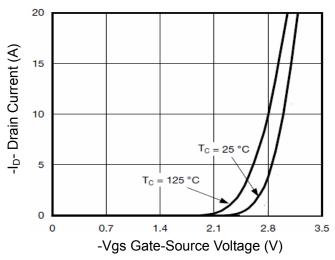


Figure 2 Transfer Characteristics

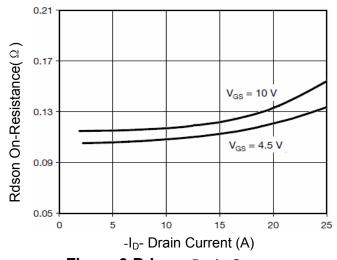


Figure 3 Rdson- Drain Current

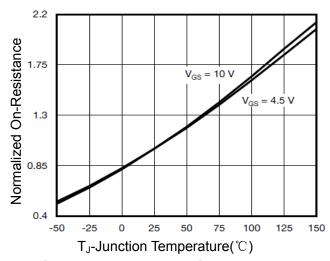


Figure 4 Rdson-JunctionTemperature

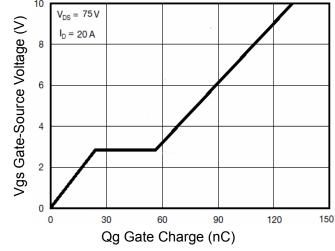


Figure 5 Gate Charge

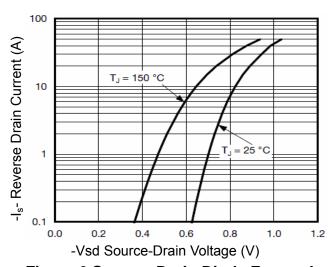


Figure 6 Source- Drain Diode Forward

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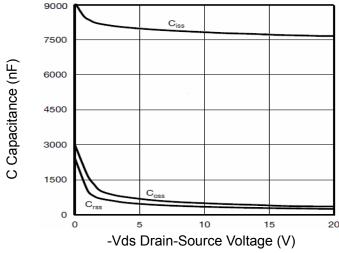


Figure 7 Capacitance vs Vds

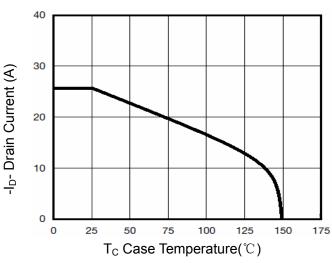


Figure 9 Drain Current vs Case Temperature

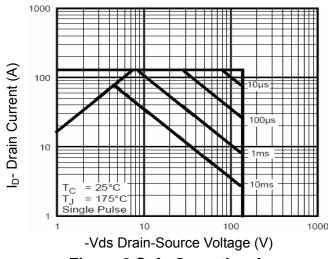


Figure 8 Safe Operation Area

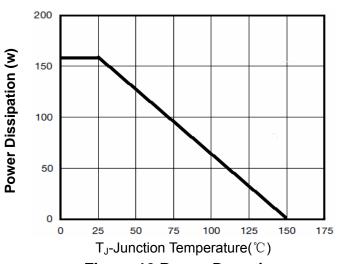


Figure 10 Power De-rating

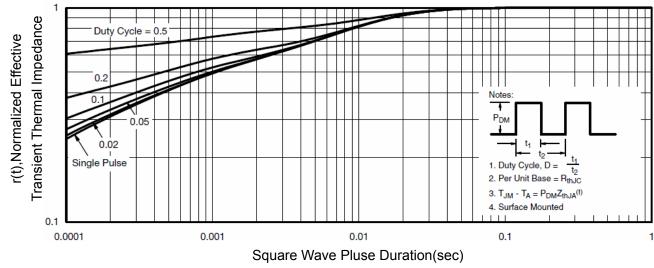
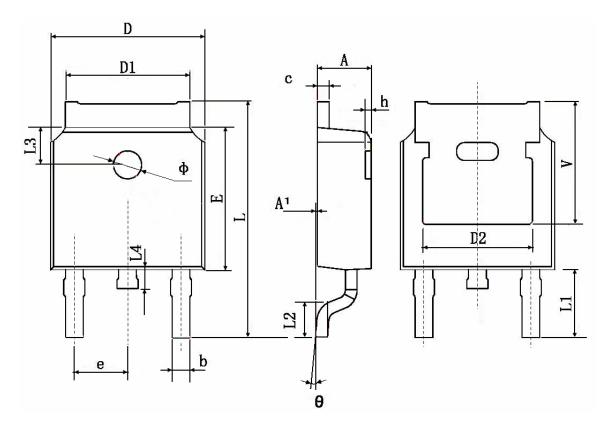


Figure 11 Normalized Maximum Transient Thermal Impedance

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TO-252 Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches		
	Min.	Max.	Min.	Max.	
A	2.200	2.400	0.087	0.094	
A1	0.000	0.127	0.000	0.005	
b	0.660	0.860	0.026	0.034	
С	0.460	0.580	0.018	0.023	
D	6.500	6.700	0.256	0.264	
D1	5.100	5.460	0.201	0.215	
D2	4.83 TYP.		0.190 TYP.		
Е	6.000	6.200	0.236	0.244	
е	2.186	2.386	0.086	0.094	
L	9.800	10.400	0.386	0.409	
L1	2.900 TYP.		0.114 TYP.		
L2	1.400	1.700	0.055	0.067	
L3	1.600 TYP.		0.063 TYP.		
L4	0.600	1.000	0.024	0.039	
Ф	1.100	1.300	0.043	0.051	
θ	0°	8°	0°	8°	
h	0.000	0.300	0.000	0.012	
V	5.350 TYP.		0.211 TYP.		



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